V93000 Smart Scale™ Test Platform

Scalable platform combines the versatility to test all types of semiconductor devices with "smart" per-pin capabilities, enabling the industry's most cost-efficient test solutions

Reducing the cost of test requires not only innovative technology, but also an extendable system architecture to ensure long equipment lifetime for the greatest return on customers' capital investments. ADVANTEST's V93000 Smart Scale test platform is the semiconductor industry's first scalable, highly cost-efficient ATE solution to meet these criteria, addressing the needs of leading IDMs, foundries, design houses and OSATs around the world.

Solutions for Advanced CMOS

The V93000 Smart Scale generation is designed to meet the challenges of testing advanced, high-integration CMOS technology. Increased test coverage, faster time-to-market and superior test economics are achieved with industry-leading digital performance, high-speed I/O flexibility, system-like stress testing, protocol-engine-per-pin™ capabilities, real-time memory emulation, SmartLoop™ testing of symmetrical high-speed interfaces and enhanced SmarTest™ software functionality.

Smarter Testing

ADVANTEST's V93000 Smart Scale generation incorporates innovative per-pin testing capabilities. Each pin can run with its own clock domain to match the exact data rate requirements of the device under test, providing full test coverage. In addition, the testers are equipped for power supply modulation, jitter injection and protocol communication

.Application-specific Configurations

This versatile platform is available in various configurations, each optimized to meet the customer's distinct performance and economic requirements:

- The **V93000 Versatile Digital solution** addresses all aspects of testing digital ICs, from wafer sorting to high-end characterization.
- For ICs for mobile applications, the **V93000 Wireless/RF solution** can handle up to 96 ports with true octal-site and high multi-site parallel efficiency at a minimal cost of test.
- The **V93000 SOC solution** performs economic testing of high-volume, cost-sensitive ICs while satisfying the testing challenges of the latest mixed-signal devices used in consumer electronics.

Scalable Tester Classes

Systems are available in four different classes – designated A, C, S and L – featuring different test head sizes to provide the most effective solution for each user's specific applications. These compatible tester classes allow users to quickly and easily move their semiconductor devices from one Smart Scale class to another as IC production volumes change over time.

ADVANTEST

http://www.advantest.com